**PCN Number:** 20130501002 **PCN Date:** 05/03/2013 Title: Gladiator revision change from rev B to C **Customer Contact:** PCN Manager **Phone:** +1(214)480-6037 Dept: **Quality Services Proposed 1<sup>st</sup> Ship Date:** 08/03/2013 **Estimated Sample Availability:** 06/01/2013 **Change Type:** Assembly Site **Assembly Process Assembly Materials Electrical Specification** Mechanical Specification Design Test Site Packing/Shipping/Labeling **Test Process** Wafer Bump Material Wafer Bump Process Wafer Bump Site Wafer Fab Site Wafer Fab Materials Wafer Fab Process **PCN Details** 

## **Description of Change:**

Purpose of making the change from revision B to C is to update the die for Errata DEVICE\_056, NHET\_52, NHET\_53, SYS\_111

#### **Reason for Change:**

Resolution of silicon erratas on rev B

### Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

## Changes to product identification resulting from this PCN:

Current	New
Die REV (2P)	Die REV (2P)
В	С

Note: The [2P] location on the label will be 'C' for the new material.

Sample product shipping label (**not** actual product label)







#### **Product Affected:**

RM48L952PGET

RM48L952ZWTT

TMS5702122BPGEQQ1

TMS5702135BZWTQQ1

TMS5703137BPGEQQ1

TMS5703137BZWTQQ1

# **Qualification Data:**

This qualification has been specifically developed for the validation of this change for ZWT and PGE packages for revision C. The qualification data validates that the proposed change meets the applicable released technical specifications.

**Qualification Schedule:** Start: 04/15/2013 End: 06/15/2013

Package Type	<u>zwt</u>	<u>PGE</u>
High Temperature Operating Life 125c (1000 hrs)	231	n/a
Temperature Humidity Bias (500 hrs)	231	n/a
ESD-HBM (2000 v)	42	42
ESD-CDM (500v all pins & 750v corner pins)	10	10
Latch-Up	6	6

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com